## STL3NM60N



# N-channel 600 V, 1.5 Ω, 2.2 A MDmesh™ II Power MOSFET in a PowerFLAT™ 3.3 x 3.3 HV package

Datasheet - production data

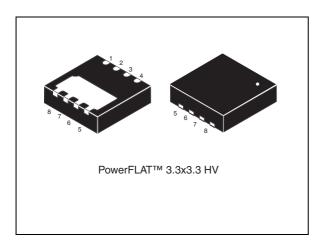
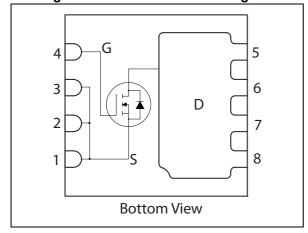


Figure 1. Internal schematic diagram



#### **Features**

Order code	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STL3NM60N	1.8 Ω	2.2 A

- 100% avalanche tested
- · Low input capacitance and gate charge
- Low gate input resistance

#### **Application**

· Switching applications

### **Description**

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary** 

Order code	Marking	Package	Packaging
STL3NM60N	3NM60N	PowerFLAT™ 3.3 x 3.3 HV	Tape and reel

Contents STL3NM60N

## **Contents**

1	Electrical ratings	3
2	Electrical characteristics	4
	2.1 Electrical characteristics (curves)	6
3	Test circuits	8
4	Package mechanical data	9
5	Revision history	12



STL3NM60N Electrical ratings

## 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	600	V
V <sub>GS</sub>	Gate-source voltage	± 25	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	2.2	Α
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> =100 °C	1.7	Α
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>amb</sub> = 25 °C	0.65	Α
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>amb</sub> =100 °C	0.5	Α
I <sub>DM</sub> <sup>(2)(3)</sup>	Drain current (pulsed)	2.6	Α
P <sub>TOT</sub> (2)	Total dissipation at T <sub>amb</sub> = 25 °C	2	W
P <sub>TOT</sub> <sup>(1)</sup>	Total dissipation at T <sub>C</sub> = 25 °C	22	W
I <sub>AS</sub>	Avalanche current, repetitive or not-repetitive <sup>(3)</sup>	1	Α
E <sub>AS</sub>	Single pulse avalanche energy (4)	119	mJ
	Derating factor <sup>(2)</sup>	0.016	W/°C
dv/dt (5)	Peak diode recovery voltage slope	15	V/ns
T <sub>J</sub> T <sub>stg</sub>	Operating junction temperature storage temperature	-55 to 150	°C

<sup>1.</sup> The value is rated according  $R_{\text{thi-case}}$ .

Table 3. Thermal resistance

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max.	5.6	°C/W
R <sub>thj-amb</sub> (1)	Thermal resistance junction-amb max.	62.5	°C/W

<sup>1.</sup> When mounted on FR-4 board of 1inch², 2oz Cu, t < 10 sec.

<sup>2.</sup> When mounted on FR-4 board of 1inch², 2oz Cu, t < 10 sec

<sup>3.</sup> Pulse width limited by Tjmax

<sup>4.</sup> Starting Tj = 25 °C, $I_D$ =  $I_{AS}$ ,  $V_{DD}$ = 50V

<sup>5.</sup>  $I_{SD} \leq 2.2 \text{ A, dv/dt} \leq 400 \text{ A/}\mu\text{s,V}_{DS} \text{ peak} \leq \text{V}_{(BR)DSS}, \text{V}_{DD} = 80\% \text{ V}_{(BR)DSS}$ 

Electrical characteristics STL3NM60N

## 2 Electrical characteristics

(T<sub>CASE</sub>=25°C unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage (V <sub>GS</sub> = 0)	I <sub>D</sub> = 1 mA	600			V
1	Zero gate voltage drain	V <sub>DS</sub> = 600 V,			1	μΑ
DSS	current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 600 V, T <sub>c</sub> = 125 °C			100	μΑ
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 25 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1 A		1.5	1.8	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	188	-	pF
C <sub>oss</sub>	Output capacitance	$V_{DS} = 50V$ , f=1 MHz,	-	13	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	V <sub>GS</sub> =0	-	1.1	-	pF
C <sub>oss eq.</sub> (1)	Output equivalent capacitance	V <sub>GS</sub> =0, V <sub>DS</sub> =0 to 480 V	-	100	-	pF
R <sub>g</sub>	Gate input resistance	f =1 MHz gate DC bias=0 test signal level = 20 mV open drain	-	6	-	Ω
Qg	Total gate charge	V <sub>DD</sub> = 480 V, I <sub>D</sub> = 2.2 A	-	9.5	-	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> =10 V (see Figure 15)	-	1.6	-	nC
Q <sub>gd</sub>	Gate-drain charge		-	5.3	-	nC

<sup>1.</sup>  $C_{\rm oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{\rm oss}$  when  $V_{\rm DS}$  increases from 0 to 80%  $V_{\rm DSS}$ 



### Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time		-	8.6	-	ns
t <sub>r</sub>	Rise time	$V_{DD}$ = 300 V, $I_{D}$ = 1.1 A, $R_{G}$ = 4.7 $\Omega$ , $V_{GS}$ = 10 V	-	6.2	-	ns
t <sub>d(off)</sub>	Turn-off delay time	(see Figure 14)	-	20.8	-	ns
t <sub>f</sub>	Fall time		-	20	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I <sub>SD</sub>	Source-drain current		-		2.2	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		8.8	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 2.2 A, V <sub>GS</sub> =0	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 2.2 A,	1	168		ns
$Q_{rr}$	Reverse recovery charge	di/dt = 100  A/µs,	-	672		nC
I <sub>RRM</sub>	Reverse recovery current	V <sub>DD</sub> = 60 V (see Figure 16)	1	8		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 2.2 A,	-	2.3		ns
Q <sub>rr</sub>	Reverse recovery charge	di/dt = 100 A/μs, - V <sub>DD</sub> = 60 V, Tj= 150 °C	-	913		nC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 16)	-	9		Α

<sup>1.</sup> Pulse width limited by safe operating area.

<sup>2.</sup> Pulsed: pulse duration =  $300 \mu s$ , duty cycle 1.5%

Electrical characteristics STL3NM60N

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance

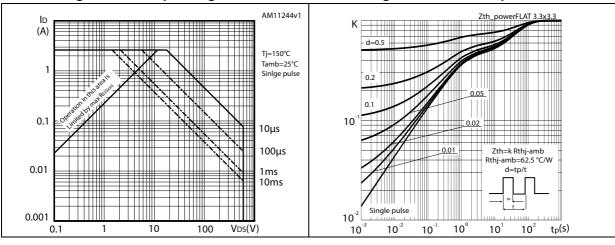


Figure 4. Output characteristics

Figure 5. Transfer characteristics

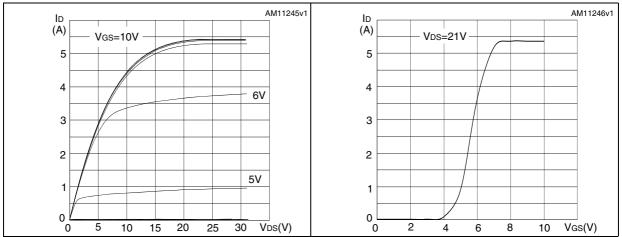
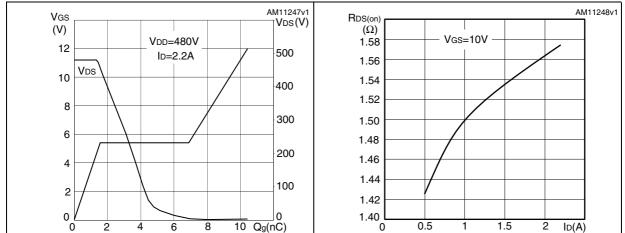


Figure 6. Gate charge vs gate-source voltage

Figure 7. Static drain-source on resistance

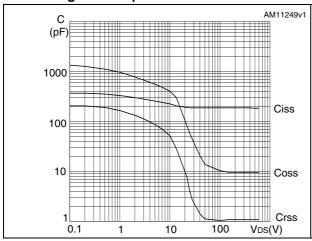


6/13 DocID022795 Rev 2

57

Figure 8. Capacitance variations

Figure 9. Output capacitance stored energy



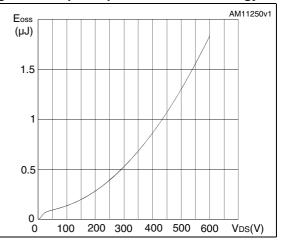
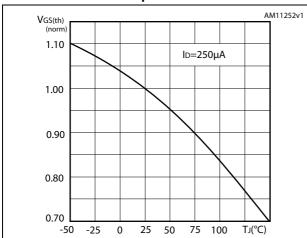


Figure 10. Normalized gate threshold voltage vs temperature

Figure 11. Normalized on resistance vs temperature



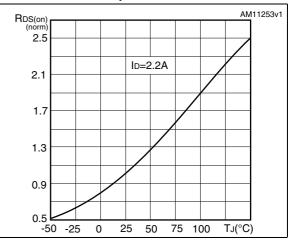
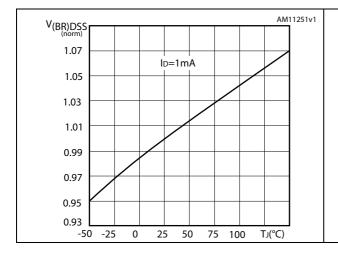
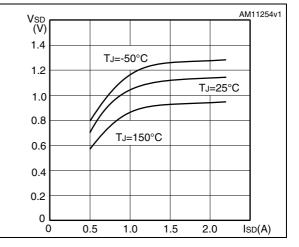


Figure 12. Normalized  $V_{(BR)DSS}$  vs temperature

Figure 13. Source-drain diode forward characteristics





57/

Test circuits STL3NM60N

## 3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

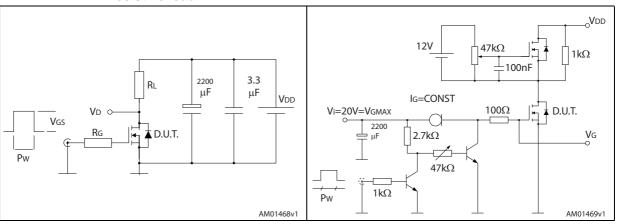


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

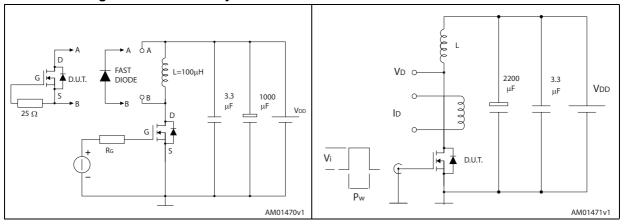
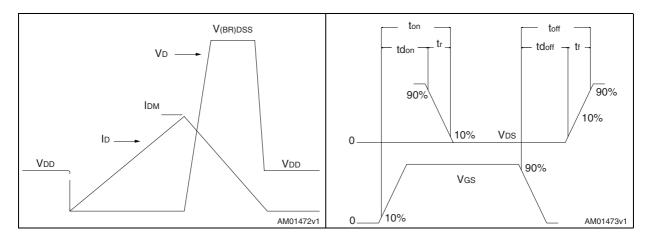


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



8/13 DocID022795 Rev 2



# 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.



DocID022795 Rev 2

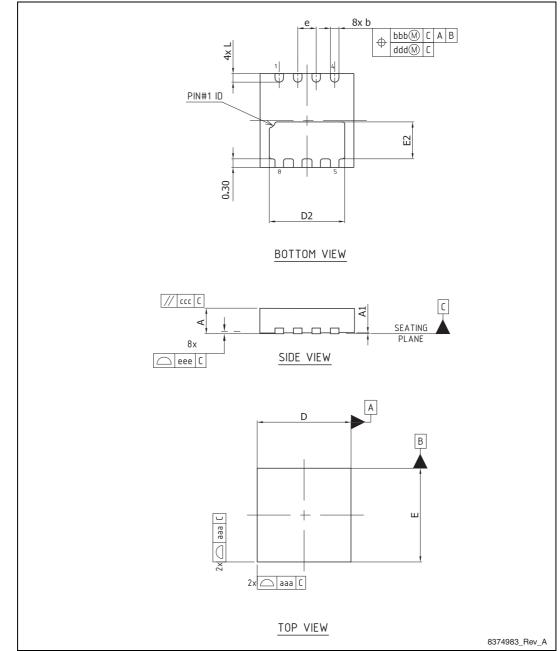


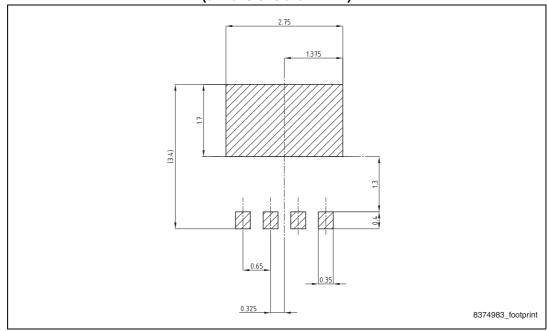
Figure 20. PowerFLAT™ 3.3 x 3.3 HV drawing

577

Table 8. PowerFLAT™ 3.3 x 3.3 HV mechanical data

Dim.		mm	
Dilli.	Min.	Typ.	Max.
А	0.80	0.90	1.00
A1	0	0.02	0.05
b	0.25	0.30	0.40
D		3.30	
D2	2.50	2.65	2.75
E		3.30	
E2	1.15	1.30	1.40
е		0.65	
L	0.20	0.30	0.40
aaa		0.10	
bbb		0.10	
ccc		0.10	
ddd		0.05	
eee		0.08	

Figure 21. PowerFLAT™ 3.3 x 3.3 HV recommended footprint (dimensions are in mm)





DocID022795 Rev 2

Revision history STL3NM60N

# 5 Revision history

**Table 9. Document revision history** 

Date	Revision	Changes
12-Mar-2012	1	First release.
19-Nov-2014	2	Document status changed from preliminary to production data.  Updated Figure 1.: Internal schematic diagram, Figure 2.: Safe operating area, Figure 3.: Thermal impedance and Figure 12.: Normalized V <sub>(BR)DSS</sub> vs temperature.  Updated Table 5.: Dynamic and Table 7.: Source drain diode.  Minor text changes.

12/13 DocID022795 Rev 2

#### **IMPORTANT NOTICE - PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2014 STMicroelectronics - All rights reserved



DocID022795 Rev 2

13/13